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Embedded - FPGAs (Field Programmable Gate Array) with Microcontrollers: Enhancing Flexibility and Performance

Embedded - FPGAs (Field Programmable Gate

Arrays) with Microcontrollers represent a cutting-edge category of electronic components that combine the flexibility of FPGA technology with the processing power of integrated microcontrollers. This hybrid approach offers a versatile solution for designing and implementing complex digital systems that require both programmable logic and embedded processing capabilities.

What Are Embedded - FPGAs with Microcontrollers?

At their care EDCAs are comicanductor devices that can

Details

Product Status	Obsolete
Core Type	8-Bit AVR
Speed	25 MHz
Interface	I ² C, UART
Program SRAM Bytes	4К-16К
FPGA SRAM	2kb
EEPROM Size	-
Data SRAM Bytes	4K ~ 16K
FPGA Core Cells	256
FPGA Gates	5К
FPGA Registers	436
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/at94k05al-25ajc

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Figure 1. FPSLIC Device Date Code with JTAG ICE Support

The AT94K series architecture is shown in Figure 2.

Figure 2. AT94K Series Architecture





FPGA Core	
	The AT40K core can be used for high-performance designs, by implementing a variety of com- pute-intensive arithmetic functions. These include adaptive finite impulse response (FIR) filters, fast Fourier transforms (FFT), convolvers, interpolators, and discrete-cosine transforms (DCT) that are required for video compression and decompression, encryption, convolution and other multimedia applications.
Fast, Flexible and Efficient SRAM	The AT40K core offers a patented distributed 10 ns SRAM capability where the RAM can be used without losing logic resources. Multiple independent, synchronous or asynchronous, dual-port or single-port RAM functions (FIFO, scratch pad, etc.) can be created using Atmel's macro generator tool.
Fast, Efficient Array and Vector Multipliers	The AT40K cores patented 8-sided core cell with direct horizontal, vertical and diagonal cell- to-cell connections implements ultra-fast array multipliers without using any busing resources. The AT40K core's Cache Logic capability enables a large number of design coefficients and variables to be implemented in a very small amount of silicon, enabling vast improvement in system speed.
Cache Logic Design	The AT40K FPGA core is capable of implementing Cache Logic (dynamic full/partial logic reconfiguration, without loss of data, on-the-fly) for building adaptive logic and systems. As new logic functions are required, they can be loaded into the logic cache without losing the data already there or disrupting the operation of the rest of the chip; replacing or complementing the active logic. The AT40K FPGA core can act as a reconfigurable resource within the FPSLIC environment.
Automatic Component Generators	The AT40K is capable of implementing user-defined, automatically generated, macros; speed and functionality are unaffected by the macro orientation or density of the target device. This enables the fastest, most predictable and efficient FPGA design approach and minimizes design risk by reusing already proven functions. The Automatic Component Generators work seamlessly with industry-standard schematic and synthesis tools to create fast, efficient designs.
	The patented AT40K architecture employs a symmetrical grid of small yet powerful cells con- nected to a flexible busing network. Independently controlled clocks and resets govern every column of four cells. The FPSLIC device is surrounded on three sides by programmable I/Os.
	Core usable gate counts range from 5,000 to 40,000 gates and 436 to 2,864 registers. Pin locations are consistent throughout the FPSLIC family for easy design migration in the same package footprint.
	The Atmel AT40K FPGA core architecture was developed to provide the highest levels of per- formance, functional density and design flexibility. The cells in the FPGA core array are small, efficient and can implement any pair of Boolean functions of (the same) three inputs or any single Boolean function of four inputs. The cell's small size leads to arrays with large numbers of cells. A simple, high-speed busing network provides fast, efficient communication over medium and long distances.
The Symmetrical Array	At the heart of the Atmel FPSLIC architecture is a symmetrical array of identical cells. The array is continuous from one edge to the other, except for bus repeaters spaced every four cells, see Figure 3. At the intersection of each repeater row and column is a 32 x 4 RAM block accessible by adjacent buses. The RAM can be configured as either a single-ported or dual-ported RAM, with either synchronous or asynchronous operation.









Note: 1. Two on left edge column of the embedded FPGA array only.



Program and Data SRAM

Up to 36 Kbytes of 15 ns dual-port SRAM reside between the FPGA and the AVR. This SRAM is used by the AVR for program instruction and general-purpose data storage. The AVR is connected to one side of this SRAM; the FPGA is connected to the other side. The port connected to the FPGA is used to store data without using up bandwidth on the AVR system data bus.

The FPGA core communicates directly with the data SRAM⁽¹⁾ block, viewing all SRAM memory space as 8-bit memory.

Note: 1. The unused bits for the FPGA-SRAM address must tie to '0' because there is no pull-down circuitry.

For the AT94K10 and AT94K40, the internal program and data SRAM is divided into three blocks: 10 Kbytes x 16 dedicated program SRAM, 4 Kbytes x 8 dedicated data SRAM and 6 Kbytes x 16 or 12 Kbytes x 8 configurable SRAM, which may be swapped between program and data memory spaces in 2 Kbytes x 16 or 4 Kbytes x 8 partitions.

For the AT94K05, the internal program and data SRAM is divided into three blocks: 4 Kbytes 16 dedicated program SRAM, 4 Kbytes x 8 dedicated data SRAM and 6 Kbytes x 16 or 12 Kbytes x 8 configurable SRAM, which may be swapped between program and data memory spaces in 2 Kbytes x 16 or 4 Kbytes x 8 partitions.

The addressing scheme for the configurable SRAM partitions prevents program instructions from overwriting data words and vice versa. Once configured (SCR41:40 – See "System Control Register – FPGA/AVR" on page 30.), the program memory space remains isolated from the data memory space. SCR41:40 controls internal muxes. Write enable signals allow the memory to be safely segmented. Figure 19 shows the FPSLIC configurable allocation SRAM memory.

Mnemonics	- Operands	Description	Operation	Flags	#Clock
ST	-Y. Br	Store Indirect and Pre-Decrement	$Y \leftarrow Y - 1$. (Y) $\leftarrow Br$	None	2
STD	Y+q, Rr	Store Indirect with Displacement	$(Y + q) \leftarrow Rr$	None	2
ST	Z, Rr	Store Indirect	$(Z) \leftarrow Rr$	None	2
ST	Z+, Rr	Store Indirect and Post-Increment	$(Z) \leftarrow Rr, Z \leftarrow Z + 1$	None	2
ST	-Z, Rr	Store Indirect and Pre-Decrement	$Z \leftarrow Z - 1$, (Z) $\leftarrow Rr$	None	2
STD	Z+q, Rr	Store Indirect with Displacement	$(Z + q) \leftarrow Rr$	None	2
LPM		Load Program Memory	$R0 \leftarrow (Z)$	None	3
LPM	Rd, Z	Load Program Memory	$Rd \leftarrow (Z)$	None	3
LPM	Rd, Z+	Load Program Memory and Post- Increment	$Rd \leftarrow (Z), Z \leftarrow Z + 1$	None	3
IN	Rd, A	In From I/O Location	$Rd \leftarrow I/O(A)$	None	1
OUT	A, Rr	Out To I/O Location	I/O(A) ← Rr	None	1
PUSH	Rr	Push Register on Stack	$STACK \gets Rr$	None	2
POP	Rd	Pop Register from Stack	$Rd \leftarrow STACK$	None	2
		Bit and Bit-tes	t Instructions		
LSL	Rd	Logical Shift Left	$Rd(n+1) \leftarrow Rd(n), Rd(0) \leftarrow 0, C \leftarrow Rd(7)$	Z,C,N,V,H	1
LSR	Rd	Logical Shift Right	$Rd(n) \leftarrow Rd(n+1), Rd(7) \leftarrow 0, C \leftarrow Rd(0)$	Z,C,N,V	1
ROL	Rd	Rotate Left Through Carry	$Rd(0) \leftarrow C, Rd(n+1) \leftarrow Rd(n), C \leftarrow Rd(7)$	Z,C,N,V,H	1
ROR	Rd	Rotate Right Through Carry	$Rd(7)\leftarrow C,Rd(n)\leftarrow Rd(n+1),C\leftarrow Rd(0)$	Z,C,N,V	1
ASR	Rd	Arithmetic Shift Right	$Rd(n) \leftarrow Rd(n+1), n=06$	Z,C,N,V	1
SWAP	Rd	Swap Nibbles	$Rd(30) \leftrightarrow Rd(74)$	None	1
BSET	S	Flag Set	$SREG(s) \leftarrow 1$	SREG(s)	1
BCLR	S	Flag Clear	$SREG(s) \leftarrow 0$	SREG(s)	1
SBI	A, b	Set Bit in I/O Register	$I/O(A, b) \leftarrow 1$	None	2
CBI	A, b	Clear Bit in I/O Register	$I/O(A, b) \leftarrow 0$	None	2
BST	Rr, b	Bit Store from Register to T	$T \leftarrow Rr(b)$	Т	1
BLD	Rd, b	Bit load from T to Register	$Rd(b) \leftarrow T$	None	1
SEC		Set Carry	C ← 1	С	1
CLC		Clear Carry	C ← 0	С	1
SEN		Set Negative Flag	N ← 1	Ν	1
CLN		Clear Negative Flag	N ← 0	Ν	1
SEZ		Set Zero Flag	Z ← 1	Z	1
CLZ		Clear Zero Flag	Z ← 0	Z	1
SEI		Global Interrupt Enable	← 1	I	1
CLI		Global Interrupt Disable	l ← 0	I	1
SES		Set Signed Test Flag	S ← 1	S	1

Instruction Set Summary (Continued)



General AVR/FPGA I/O Select Procedure

I/O select depends on the FISCR register setup and the FISUA..D register written to or read from.

The following FISCR setups and writing data to the FISUA..D registers will result in the shown I/O select lines and data presented on the 8-bit AVR-FPGA data bus.

Table 14. FISCR Register Setups and I/O Select Lines.

FISCR Register			I/O Select Lines ⁽¹⁾				
FIADR(b7)	b6-2	XFIS1(b1)	XFIS0(b0)	FISUA	FISUB	FISUC	FISUD
0	-	0	0	IOSEL 0	IOSEL 4	IOSEL 8	IOSEL 12
0	-	0	1	IOSEL 1	IOSEL 5	IOSEL 9	IOSEL 13
0	-	1	0	IOSEL 2	IOSEL 6	IOSEL 10	IOSEL 14
0	-	1	1	IOSEL 3	IOSEL 7	IOSEL 11	IOSEL 15

Note: 1. IOSEL 15..8 are not available on AT94K05.

;-----

io_	sel	ect()_1	vrite:	
-			-		

ldi r16,0x00	;FIADR=0,XFIS1=0,XFIS0=0 ->I/0 select line=0
out FISCR,r16	;load I/O select values into FISCR register
out FISUA,r17;	;select line 0 high. Place data on AVR<->FPGA bus
	; from r17 register. (out going data is assumed
	; to be present in r17 before calling this subroutine)
ret	

;-----

io_select13_read:

ldi r16,0x01	;FIADR=0,XFIS1=0,XFIS0=1 ->I/O select line=13
out FISCR,r16	;load I/O select values into FISCR register
in r18,FISUD	;select line 13 high. Read data on AVR<->FPGA bus
	;which was placed into register FISUD.

ret





Reset and Interrupt Handling

The embedded AVR and FPGA core provide 35 different interrupt sources. These interrupts and the separate reset vector each have a separate program vector in the program memory space. All interrupts are assigned individual enable bits (masks) which must be set (one) together with the I-bit in the status register in order to enable the interrupt.

The lowest addresses in the program memory space must be defined as the Reset and Interrupt vectors. The complete list of vectors is shown in Table 15. The list also determines the priority levels of the different interrupts. The lower the address the higher the priority level. RESET has the highest priority, and next is FPGA_INTO – the FPGA Interrupt Request 0 etc.

Vector No. (hex)	Program Address	Source	Interrupt Definition
01	\$0000	RESET	Reset Handle: Program Execution Starts Here
02	\$0002	FPGA_INT0	FPGA Interrupt0 Handle
03	\$0004	EXT_INT0	External Interrupt0 Handle
04	\$0006	FPGA_INT1	FPGA Interrupt1 Handle
05	\$0008	EXT_INT1	External Interrupt1 Handle
06	\$000A	FPGA_INT2	FPGA Interrupt2 Handle
07	\$000C	EXT_INT2	External Interrupt2 Handle
08	\$000E	FPGA_INT3	FPGA Interrupt3 Handle
09	\$0010	EXT_INT3	External Interrupt3 Handle
0A	\$0012	TIM2_COMP	Timer/Counter2 Compare Match Interrupt Handle
0B	\$0014	TIM2_OVF	Timer/Counter2 Overflow Interrupt Handle
0C	\$0016	TIM1_CAPT	Timer/Counter1 Capture Event Interrupt Handle
0D	\$0018	TIM1_COMPA	Timer/Counter1 Compare Match A Interrupt Handle
0E	\$001A	TIM1_COMPB	Timer/Counter1 Compare Match B Interrupt Handle
0F	\$001C	TIM1_OVF	Timer/Counter1 Overflow Interrupt Handle
10	\$001E	TIM0_COMP	Timer/Counter0 Compare Match Interrupt Handle
11	\$0020	TIM0_OVF	Timer/Counter0 Overflow Interrupt Handle
12	\$0022	FPGA_INT4	FPGA Interrupt4 Handle
13	\$0024	FPGA_INT5	FPGA Interrupt5 Handle
14	\$0026	FPGA_INT6	FPGA Interrupt6 Handle
15	\$0028	FPGA_INT7	FPGA Interrupt7 Handle
16	\$002A	UART0_RXC	UART0 Receive Complete Interrupt Handle

Table 15. Reset and Interrupt Vectors

Reset Sources

The embedded AVR core has five sources of reset:

- External Reset. The MCU is reset immediately when a low-level is present on the RESET or AVR RESET pin.
- Power-on Reset. The MCU is reset upon chip power-up and remains in reset until the FPGA configuration has entered Idle mode.
- Watchdog Reset. The MCU is reset when the Watchdog Timer period expires and the watchdog is enabled.
- Software Reset. The MCU is reset when the SRST bit in the Software Control register is set (one).
- JTAG AVR Reset. The MCU is reset as long as there is a logic one in the Reset Register, one of the scan chains of the JTAG system. See "IEEE 1149.1 (JTAG) Boundary-scan" on page 73.

During reset, all I/O registers except the MCU Status register are then set to their Initial Values, and the program starts execution from address \$0000. The instruction placed in address \$0000 must be a JMP – absolute jump instruction to the reset handling routine. If the program never enables an interrupt source, the interrupt vectors are not used, and regular program code can be placed at these locations. The circuit diagram in Figure 35 shows the reset logic. Table 16 defines the timing and electrical parameters of the reset circuitry.





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ruction is a output lat the JTAC nitial value	used for samplin tch will be driver G IR-register. Th s to the scan rin first time. SAMPI	g external out on the erefore, th g, to avoid _E/PRELO.	pins and load pins as soo e SAMPLE/F damaging th AD can also b	ling output p n as the EX PRELOAD s e board whe be used for t	ins with data. TEST instruc- hould also be en issuing the aking a snap-		
undetermined state when exiting the test mode. If needed, the BYPASS instruction can be issued to make the shortest possible scan chain through the device. The AVR can be set in the reset state either by pulling the external AVR RESET pin Low, or issuing the AVR_RESET instruction with appropriate setting of the Reset Data Register.							
	ate when e ne shortes her by pull propriate ruction is n o output la o the JTAC	ate when exiting the test me be shortest possible scan her by pulling the external popropriate setting of the Re ruction is used for samplin e output latch will be driver to the JTAG IR-register. Th	ate when exiting the test mode. If ne be shortest possible scan chain throu her by pulling the external AVR RESE opropriate setting of the Reset Data R ruction is used for sampling external e output latch will be driven out on the of the JTAG IR-register. Therefore, th	ate when exiting the test mode. If needed, the BY he shortest possible scan chain through the device her by pulling the external AVR RESET pin Low, or opropriate setting of the Reset Data Register. ruction is used for sampling external pins and load e output latch will be driven out on the pins as soon of the JTAG IR-register. Therefore, the SAMPLE/P	ate when exiting the test mode. If needed, the BYPASS instru- be shortest possible scan chain through the device. The AVR her by pulling the external AVR RESET pin Low, or issuing the opropriate setting of the Reset Data Register. ruction is used for sampling external pins and loading output p e output latch will be driven out on the pins as soon as the EX to the JTAG IR-register. Therefore, the SAMPLE/PRELOAD s		

Version

Version is a 4-bit number identifying the revision of the component. The relevant version numbers are shown in Table 18.

Table 18. JTAG Part Version

Device	Version (Binary Digits)
AT94K05	-
AT94K10	0010
AT94K40	-

When no alternate port function is present, the Input Data - ID corresponds to the PINn register value, Output Data corresponds to the PORTn register, Output Control corresponds to the Data Direction (DDn) register, and the PuLL-up Disable (PLD) corresponds to logic expression (DDn OR NOT(PORTBn)).

Digital alternate port functions are connected outside the dashed box in Figure 44 to make the scan chain read the actual pin value.

Scanning AVR RESET Multiple sources contribute to the internal AVR reset; therefore, the AVR reset pin is not observed. Instead, the internal AVR reset signal output from the Reset Control Unit is observed, see Figure 45. The scanned signal is active High if AVRResetn is Low and enabled or the device is in general reset (Resetn or power-on) or configuration download.



Figure 45. Observe-only Cell





I/O Ports	Description	Bit
	Data Out/In - PD7	44
	Enable Output - PD7	43
	Pull-up - PD7	42
	Data Out/In - PD6	41
	Enable Output - PD6	40
	Pull-up - PD6	39
	Data Out/In - PD5	38
	Enable Output - PD5	37
	Pull-up - PD5	36
	Data Out/In - PD4	35
	Enable Output - PD4	34
	Pull-up - PD4	33
PORTD	Data Out/In - PD3	32
	Enable Output - PD3	31
	Pull-up - PD3	30
	Data Out/In - PD2	29
	Enable Output - PD2	28
	Pull-up - PD2	27
	Data Out/In - PD1	26
	Enable Output - PD1	25
	Pull-up - PD1	24
	Data Out/In - PD0	23
	Enable Output - PD0	22
	Pull-up - PD0	21
	Input with Pull-up - INTP3	20 ⁽¹⁾
	Input with Pull-up - INTP2	19 ⁽¹⁾
EXI. INTERRUPTS	Input with Pull-up - INTP1	18 ⁽¹⁾
	Input with Pull-up - INTP0	17 ⁽¹⁾
	Data Out/In - TX1	16
UART1	Enable Output - TX1	15
	Pull-up - TX1	14
	Input with Pull-up - RX1	13 ⁽¹⁾
	Data Out/In - TX0	12
	Enable Output - TX0	11
UAR10	Pull-up - TX0	10
	Input with Pull-up - RX0	9 ⁽¹⁾

Table 20. AVR I/O Boundary Scan - JTAG Instructions \$0/\$2

16-bit x 16-bit = 16-bit Operation

This operation is valid for both unsigned and signed numbers, even though only the unsigned multiply instruction (MUL) is needed, see Figure 61. A mathematical explanation is given:

When A and B are positive numbers, or at least one of them is zero, the algorithm is clearly correct, provided that the product $C = A \cdot B$ is less than 2^{16} if the product is to be used as an unsigned number, or less than 2^{15} if the product is to be used as a signed number.

When both factors are negative, the two's complement notation is used: $A = 2^{16} - |A|$ and $B = 2^{16} - |B|$:

$$C = A \bullet B = (2^{16} - |A|) \bullet (2^{16} - |B|) = |A \bullet B| + 2^{32} - 2^{16} \bullet (|A| + |B|)$$

Here we are only concerned with the 16 LSBs; the last part of this sum will be discarded and we will get the (correct) result $C = |A \cdot B|$.

Figure 61. 16-bit Multiplication, 16-bit Result



When one factor is negative and one factor is positive, for example, A is negative and B is positive:

$$C = A \bullet B = (2^{16} - |A|) \bullet |B| = (2^{16} \bullet |B|) - |A \bullet B| = (2^{16} - |A \bullet B|) + 2^{16} \bullet (|B| - 1)$$

The MSBs will be discarded and the correct two's complement notation result will be $C = 2^{16} - |A \cdot B|$.

The product must be in the range $0 \le C \le 2^{16} - 1$ if unsigned numbers are used, and in the range $-2^{15} \le C \le 2^{15} - 1$ if signed numbers are used.

When doing integer multiplication in C language, this is how it is done. The algorithm can be expanded to do 32-bit multiplication with 32-bit result.



2-wire Serial Modes

The 2-wire Serial Interface can operate in four different modes:

- Master Transmitter
- Master Receiver
- Slave Receiver
- Slave Transmitter

Data transfer in each mode of operation is shown in Figure 71 to Figure 74. These figures contain the following abbreviations:

S: START condition

R: Read bit (High level at SDA)

W: Write bit (Low level at SDA)

A: Acknowledge bit (Low level at SDA)

A: Not acknowledge bit (High level at SDA)

Data: 8-bit data byte

P: STOP condition

In Figure 71 to Figure 74, circles are used to indicate that the 2-wire Serial Interrupt flag is set. The numbers in the circles show the status code held in TWSR. At these points, an interrupt routine must be executed to continue or complete the 2-wire Serial Transfer. The 2-wire Serial Transfer is suspended until the 2-wire Serial Interrupt flag is cleared by software.

The 2-wire Serial Interrupt flag is not automatically cleared by the hardware when executing the interrupt routine. Also note that the 2-wire Serial Interface starts execution as soon as this bit is cleared, so that all access to TWAR, TWDR and TWSR must have been completed before clearing this flag.

When the 2-wire Serial Interrupt flag is set, the status code in TWSR is used to determine the appropriate software action. For each status code, the required software action and details of the following serial transfer are given in Table 41 to Table 45.

In the Master Transmitter mode, a number of data bytes are transmitter to a Slave Receiver, see Figure 71. Before the Master Transmitter mode can be entered, the TWCR must be initialized as shown in Table 38.

Table 38. TWCR: Master Transmitter Mode Initialization

TWCR	TWINT	TWEA	TWSTA	TWSTO	TWWC	TWEN	-	TWIE
value	0	Х	0	0	0	1	0	Х

TWEN must be set to enable the 2-wire Serial Interface, TWSTA and TWSTO must be cleared.

The Master Transmitter mode may now be entered by setting the TWSTA bit. The 2-wire Serial Logic will now test the 2-wire Serial Bus and generate a START condition as soon as the bus becomes free. When a START condition is transmitted, the 2-wire Serial Interrupt flag (TWINT) is set by the hardware, and the status code in TWSR will be \$08. TWDR must then be loaded with the Slave address and the data direction bit (SLA+W). The TWINT flag must then be cleared by software before the 2-wire Serial Transfer can continue. The TWINT flag is cleared by writing a logic 1 to the flag.

When the Slave address and the direction bit have been transmitted and an acknowledgment bit has been received, TWINT is set again and a number of status codes in TWSR are possible. Status codes \$18, \$20, or \$38 apply to Master mode, and status codes \$68, \$78, or \$B0 apply to Slave mode. The appropriate action to be taken for each of these status codes is



Master

Transmitter Mode



Table 46. DDDn⁽¹⁾ Bits on PortD Pins

DDDn ⁽¹⁾	PORTDn ⁽¹⁾	I/O	Pull-up	Comment
0	0	Input	No	Tri-state (High-Z)
0	1	Input	Yes	PDn will source current if external pulled low (default)
1	0	Output	No	Push-pull zero output
1	1	Output	No	Push-pull one output

Note: 1. n: 7,6...0, pin number





PortE

PortE is an 8-bit bi-directional I/O port with internal pull-up resistors.

Three I/O memory address locations are allocated for the PortE, one each for the Data Register – PORTE, \$07(\$27), Data Direction Register – DDRE, \$06(\$26) and the PortE Input Pins – PINE, \$05(\$25). The PortE Input Pins address is read only, while the Data Register and the Data Direction Register are read/write.

The PortE output buffers can sink 20 mA. As inputs, PortE pins that are externally pulled Low will source current if the pull-up resistors are activated.

All PortE pins have alternate functions as shown in Table 47.



PortE Schematic Diagram (Pin PE3)





Figure 80. PortE Schematic Diagram (Pin PE5)





Ordering Information

Usable Gates	Speed Grade	Ordering Code	Package	Operation Range
5,000	-25 MHz	AT94K05AL-25AJC AT94K05AL-25AQC AT94K05AL-25BQC AT94K05AL-25DQC	84J 100A 144L1 208Q1	Commercial (0°C - 70°C)
		AT94K05AL-25AJI AT94K05AL-25AQI AT94K05AL-25BQI AT94K05AL-25DQI	84J 100A 144L1 208Q1	Industrial (-40°C - 85°C)
10,000	-25 MHz	AT94K10AL-25AJC AT94K10AL-25AQC AT94K10AL-25BQC AT94K10AL-25DQC	84J 100A 144L1 208Q1	Commercial (0°C - 70°C)
		AT94K10AL-25AJI AT94K10AL-25AQI AT94K10AL-25BQI AT94K10AL-25DQI	84J 100A 144L1 208Q1	Industrial (-40°C - 85°C)
40,000	-25 MHz	AT94K40AL-25BQC AT94K40AL-25DQC	144L1 208Q1	Commercial (0°C - 70°C)
		AT94K40AL-25BQI AT94K40AL-25DQI	144L1 208Q1	Industrial (-40°C - 85°C)

Package Type				
84J	84-lead, Plastic J-leaded Chip Carrier (PLCC)			
100A	100-lead, Thin (1.0 mm) Plastic Quad Flat Package (TQFP)			
144L1	144-lead, Low Profile Plastic Gull Wing Quad Flat Package (LQFP)			
208Q1	208-lead, Plastic Gull Wing Quad Flat Package (PQFP)			

Packaging Information

84J – PLCC





Thermal Coefficient Table

Package Style	Lead Count	Theta J-A 0 LFPM	Theta J-A 225 LFPM	Theta J-A 500 LPFM	Theta J-C
PLCC	84	37	30	25	12
TQFP	100	47	39	33	22
LQFP	144	33	27	23	8.5
PQFP	208	32	28	24	10





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